

IMPROVED BOLOMETER OPERATION USING FAST SCANNING

Abstract of the Disclosure

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A method and apparatus to apply two or more bias pulses sequentially to each of the microbolometers of an array during each frame time, then measuring the resulting signals associated with each of the two or more bias pulses, then computing an average signal value in each frame time for each microbolometer, 10 resulting in more uniform microbolometer temperature and improved sensitivity to infrared radiation.

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